Applicant(s)/Patent Under Application/Control No. Reexamination 10/049,438 NAKAJIMA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 1713 Rip A. Lee **U.S. PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date MM-YYYY Classification Name US-US-В US-С US-D US-E US-F US-G USн US-US-US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Country Code-Number-Kind Code Date Country Name Classification MM-YYYY CA 2,253,515 03-1998 Canada Aoyama et al. C08G 63/84 Ν 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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